

FDMB506P

P-Channel 1.8V Logic Level PowerTrench® MOSFET

General Description

This P-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance. These devices are well suited for portable electronics applications.

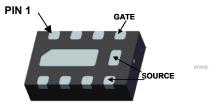
Applications

- Load switch
- DC/DC Conversion

Features

- -6.8 A, -20V. $R_{DS(ON)} = 30 \text{ m}\Omega$ @ $V_{GS} = -4.5V$ $R_{DS(ON)} = 38 \text{ m}\Omega$ @ $V_{GS} = -2.5V$ $R_{DS(ON)} = 70 \text{ m}\Omega$ @ $V_{GS} = -1.8V$
- Low profile 0.8 mm maximum
- · Fast switching
- RoHS compliant





MicroFET

3x1.9

S 5 4 G
D 6 3 D
D 7 2 D
D 8 1 D

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		±8	V
I _D	Drain Current - Continuous	(Note 1a)	-6.8	Α
	– Pulsed		70	
P _D	Power Dissipation	(Note 1a)	1.9	W
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	65	°C/W
Rela	Thermal Resistance, Junction-to-Ambient	(Note 1b)	208	

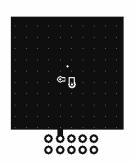
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
506	FDMB506P	7"	8mm	3000 units

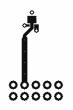
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = -250 \mu\text{A}$	-20			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V			-1	μА
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)			-		
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.4	-0.7	-1.5	V
$\Delta V_{GS(th)} \over \Delta T_{,J}$	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -6.8 \text{ A}$ $V_{GS} = -2.5 \text{ V}, I_D = -2.5 \text{ A}$ $V_{GS} = -1.8 \text{ V}, I_D = -1.8 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -6.8 \text{ A}, T_J = 125 ^{\circ}\text{C}$		25 30 40 36	30 38 70 44	mΩ
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -6.8 \text{ A}$		26		S
	Characteristics			•	•	
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$		2216	2960	pF
Coss	Output Capacitance	f = 1.0 MHz		351	470	pF
C _{rss}	Reverse Transfer Capacitance			167	260	pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_{D} = -1 \text{ A},$		14	25	ns
t _r	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		8	16	ns
t _{d(off)}	Turn-Off Delay Time			175	280	ns
t _f	Turn-Off Fall Time]		80	128	ns
Q_g	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -6.8 \text{ A},$		21	30	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -4.5 V		3.5		nC
Q_{gd}	Gate-Drain Charge			4.5		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings	1	•		•
Is	Maximum Continuous Drain-Sourc	· ·			1.6	Α
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{S} = -0.8 \text{ A}(\text{Note 2})$		-0.6	-1.2	V
t _{rr}	Diode Reverse Recovery Time	$I_F = -6.8 \text{ A},$		26	48	nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_{t} = 100 \text{ A/}\mu\text{s}$		12	22	nC

Notes:

1. R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the junction of the junction to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the junction of the junction to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the junction of the junction to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the junction of the ju the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



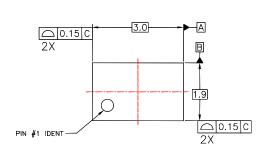
50°C/W when mounted on a 1in² pad of 2 oz copper

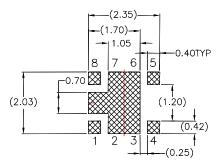


b) 160°C/W when mounted on a minimum pad of 2 oz copper Scale 1 : 1 on letter size paper

^{2.} Pulse Test: Pulse Width < $300\mu s$, Duty Cycle < 2.0%

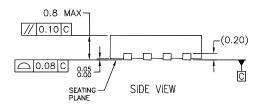
Dimensional Outline and Pad Layout

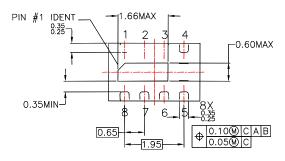




TOP VIEW

RECOMMENDED LAND PATTERN





BOTTOM VIEW

NOTES:

- DOES NOT FULLY CONFORM TO JEDEC REGISTRATION, MO-229, DATED 11/2001.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

Typical Characteristics

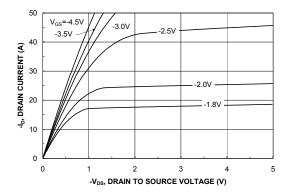


Figure 1. On-Region Characteristics.

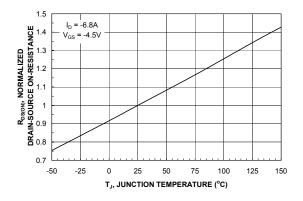


Figure 3. On-Resistance Variation with Temperature.

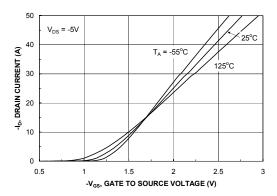


Figure 5. Transfer Characteristics.

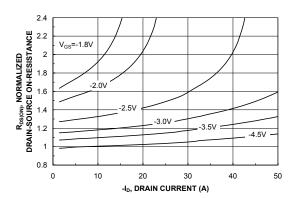


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

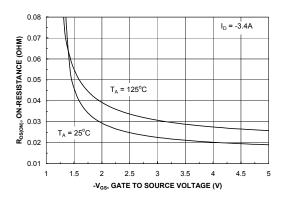


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

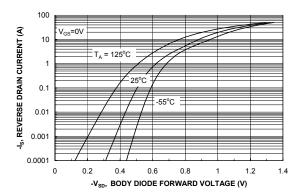
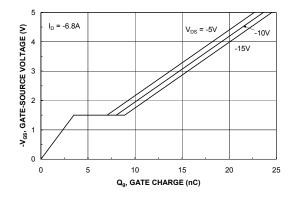


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



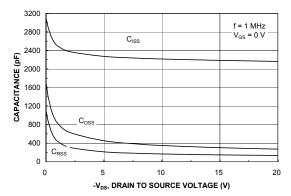
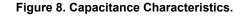
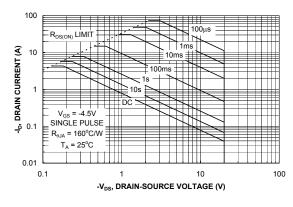


Figure 7. Gate Charge Characteristics.





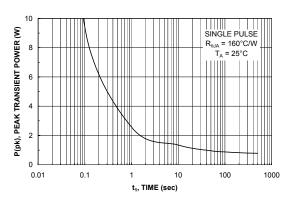


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

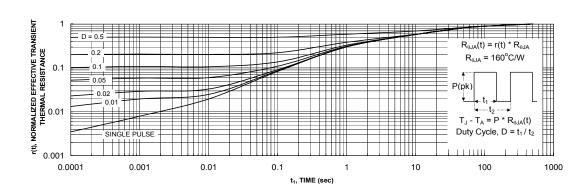


Figure 9. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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